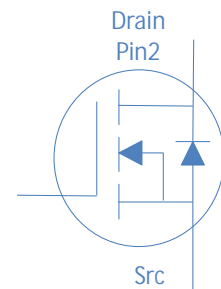


120V N-Ch Power MOSFET

V_{DS}		120	V
$R_{DS(on),typ}$	TO-252	8.6	m Ω
I_D (Silicon Limited)		102	A
I_D (Package Limited)		70	A



Part Number	Package	Marking
HGD100N12S	TO-252	GD100N12S

Absolute Maximum Ratings at $T_J=25$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	I_D	$T_C=25$	102	A
		$T_C=100$	72	
Continuous Drain Current (Package Limited)		$T_C=25$	70	
Drain to Source Voltage	V_{DS}	-	120	V
Gate to Source Voltage	V_{GS}	-	± 20	V
Pulsed Drain Current	I_{DM}	-	280	A
Avalanche Energy, Single Pulse	E_{AS}	$L=0.4mH, T_C=25$	320	mJ
Power Dissipation	P_D	$T_C=25$	188	W
Operating and Storage Temperature	T_J, T_{stg}	-	-55 to 175	

Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Case	$R_{\theta JC}$	0.8	$^{\circ}C/W$
Thermal Resistance Junction-Ambient	$R_{\theta JA}$	50	$^{\circ}C/W$

Electrical Characteristics at $T_j=25$ (unless otherwise specified)

Static Characteristics

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu A$	120	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\mu A$	2	3	4	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS}=0V, V_{DS}=120V, T_j=25$	-	-	1	μA
		$V_{GS}=0V, V_{DS}=120V, T_j=100$	-	-	100	
Gate to Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	8.6	10	m Ω
Transconductance	g_{fs}	$V_{DS}=5V, I_D=20A$	-	65	-	S
		$V_{GS}=0V, V_{DS}$ Open, $f=1MHz$	-	3.5	-	Ω

Dynamic Characteristics

Input Capacitance	C_{iss}		-	4470	-	
Output Capacitance	C_{oss}	$V_{GS}=0V, V_{DS}=60V, f=1MHz$	-	235	-	pF
Reverse Transfer Capacitance	C_{rss}		-	9.5	-	
Total Gate Charge	Q_g		-	56	-	
Gate to Source Charge	Q_{gs}	$V_{DD}=60V, I_D=20A, V_{GS}=10V$	-	18	-	nC
Gate to Drain (Miller) Charge	Q_{gd}		-	6	-	
			-	16	-	
	t_r		-	38	-	

Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_F=20A$	-			
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Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

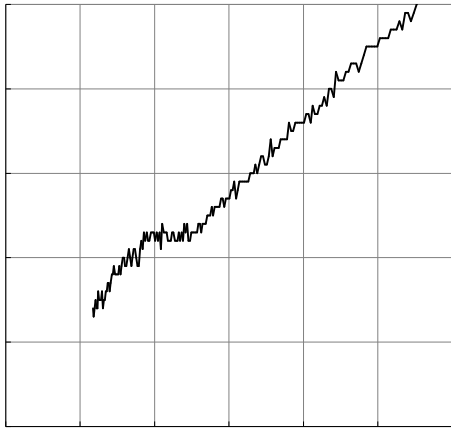


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

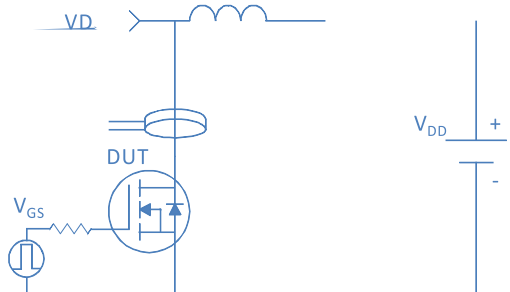
Figure 9. Maximum Safe Operating Area

Figure 10. Maximun Drain Current vs. Case Temperature

Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Case

Inductive switching Test	

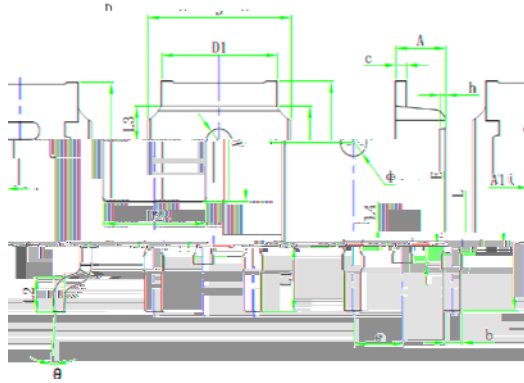
Gate Charge Test	

Uclamped Inductive Switching (UIS) Test	
	

Diode Recovery Test	

Package Outline

TO-252, 2 leads



c.	Min.	Max.	Symbol	Min.	Max.
2.200	2.400	0.087	0.094	A	
0.000	0.127	0.000	0.005	A1	
0.660	0.860	0.026	0.034	b	
0.460	0.580	0.018	0.023	c	
6.500	6.700	0.256	0.264	D	
5.100	5.460	0.201	0.215	D1	
4.830 REF.		0.190 REF.		D2	
6.000	6.200	0.236	0.244	E	
2.186	2.386	0.086	0.094	e	
9.800	10.400	0.386	0.409	L	
2.900 REF.		0.114 REF.		L1	
1.400	1.700	0.055	0.067	L2	
1.600 REF.		0.063 REF.		L3	
0.600	1.000	0.024	0.039	L4	
1.100	1.300	0.043	0.051	Φ	
0°	8°	0°	8°	θ	0
0.00	0.300	0.000	0.012	h	0.0
5.350 REF.		0.211 REF.		V	